Special Issue

Pattern Recognition and Intelligent System: Emerging Techniques and Advances

Message from the Guest Editors

With the continuous computer technology and deep learning progress, a pattern recognition and intelligent system shows a trend of development in the following fields: the Internet of Things technology, intelligent driving technology, etc.; the integration of cross-disciplinary technology, such as computational biology, biomedical engineering and natural language processing, etc.; and the combination of deep learning and big data, such as the big model, multimodality, etc. With the development of advanced technology, intelligent algorithms will allow for more advanced productivity and thus better serve the development of the present society.

This Special Issue welcomes submissions of research results relating pattern recognition and intelligent systems. Possible topics include, but are not limited to:

Pattern recognition techniques and applications; Computer vision techniques and applications; Intelligent human–machine interaction system; Natural language processing; Machine learning; Intelligent systems; Intelligent robot applications.

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Deadline for manuscript submissions

closed (20 February 2025)



Applied Sciences

an Open Access Journal by MDPI

Impact Factor 2.5 CiteScore 5.5



mdpi.com/si/195421

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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